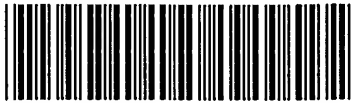


Search Notes

Application/Control No.

10/663,994

Examiner

Richard Chan

Applicant(s)/Patent under
Reexamination

HETHUIN ET AL.

Art Unit

2618

SEARCHED

Class	Subclass	Date	Examiner
455	45	6/5/2006	RC
455	106	6/5/2006	RC
340	505	6/5/2006	RC
340	572	6/5/2006	RC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR